

Efficient Experimental Methods That Enable Control Of High Pressure Microwave Discharges

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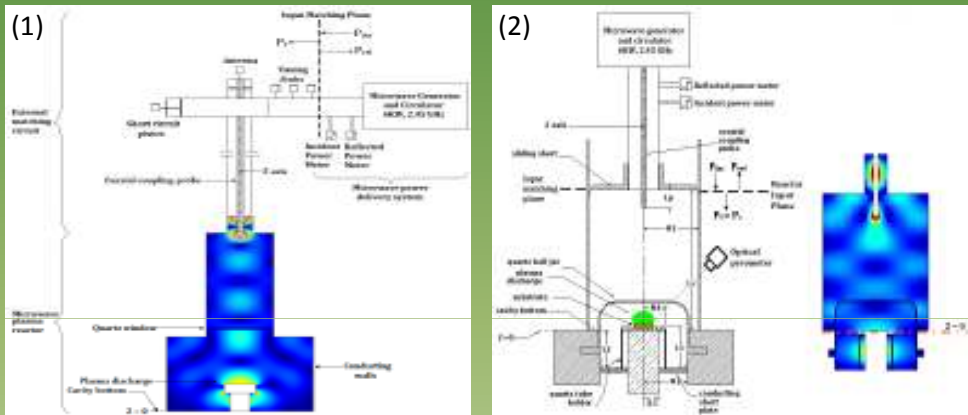
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Introduction: Microwave Plasma-Assisted CVD method is a convenient mode of synthesizing SCDs. It is important to employ an electrically efficient process producing a stable plasma for the growth process.

Experimental Details:

The main purpose of this research is to determine microwave coupling and operational efficiencies of microwave cavity plasma reactor used commercially for the synthesis of single crystal diamonds.



Operational Strategy:

- Adjust L_p and L_s to excite reactor cavity in a hybrid TM_{013}/TEM_{001} mode
- Once plasma is formed, adjust L_p , L_s , $L1$ and $L2$ for optimum operating conditions
- Measure T_{sv} , P_{inc} , P_{ref} , η with varying pressure, Z_s and L_s positions.

Important reactor variables:

1. Microwave coupling efficiency into the reactor

$$\eta = (1 - (P_w + P_{ref})/P_{inc}) \times 100\%$$

2. Overall microwave coupling efficiency into discharge

$$\eta_{coup} = (1 - (P_w + P_{ref} + P_{loss})/P_{inc}) \times 100\%$$

$$= (1 - Q_L/Q_0) \times 100\% \quad (\text{for } P_w, P_{loss} = 0)$$

3. Power coupled into discharge

$$P_{abs} = P_{inc} - P_{ref} - P_w - P_{loss}$$

where, P_w : any power lost in the external matching circuit

P_{ref} : power reflected from input matching plane

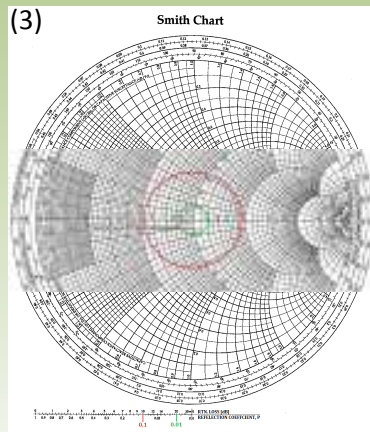
P_{inc} : incident power

P_{loss} : microwave power losses in cavity

Q_0 : Empty cavity quality factor

Q_L : discharge loaded cavity quality factor

P_{loss} is minimized by a well maintained cavity (high Q_0) and low Q_L



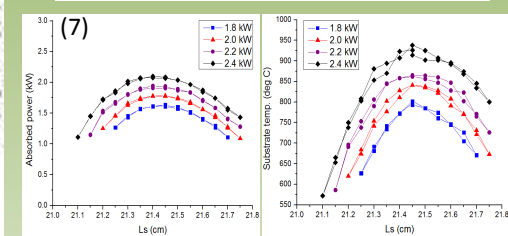
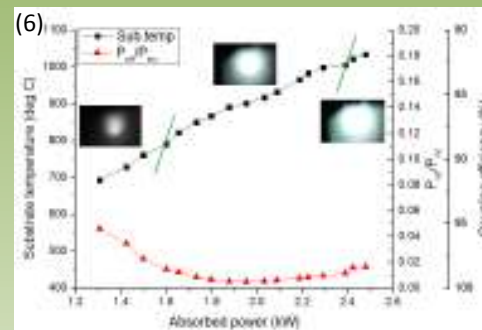
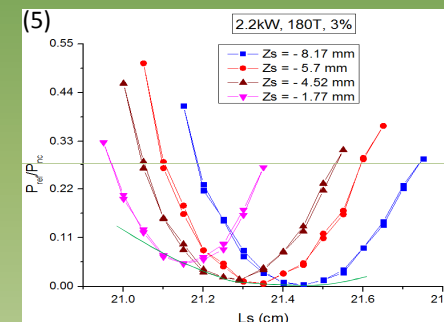
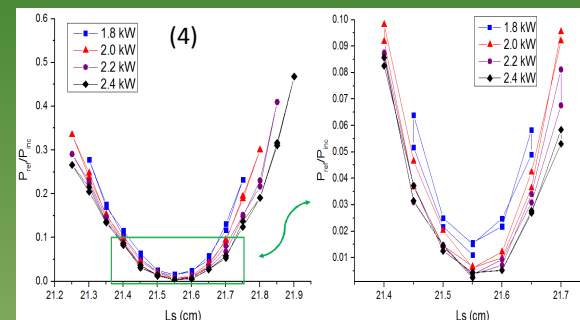
Results:

MSU reactor (fig.2) [1], has an internal matching configuration eliminating large microwave coupling power losses.

(1) Figs. 3,4 and 7 identify the “best matched” reactor position ($\eta > 98\%$) (green box/circle) at 180 Torr. For all SCD synthesis, $L_s = 21.55\text{cm}$, $\eta \sim 99\%$.

(2) Discharge boundary layer is modified when different substrate holders change L_s and hence Z_s . Fig. 5 displays the effectiveness of in situ matching. $\eta > 95\%$ at best matched positions.

(3) Operational roadmap (fig.6) describes the safe and efficient operating regime of reactor. As pressure increases the plasma intensity and size increases.



Conclusion: Internally tunable microwave reactors reduce power and high coupling efficiencies ($\eta > 95\%$) are obtained over a wide pressure and power range providing flexibility in deposition conditions. This reactor is synthesizing commercial diamond with electrical efficiency of < 10 kW-h/carat [3]. The variable substrate position enables flexible process control and optimization.

References:

- [1] J. Asmussen et.al. US Patent 8,316,797 (2012) and 8,668,962 (2014)
- [2] K.W. Hemawan et al. / Diamond & Related Materials 19 (2010) 1446–1452
- [3] J. Lu et.al. Diamond and Relat. Mater. 37, 17-28 (2013)